

<b>Notice of References Cited</b>	Application/Control No. 10/597,620		Applicant(s)/Patent Under Reexamination TAKENAKA ET AL.	
	Examiner CE LI		Art Unit 3661	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,319,918	01-2008	Takenaka et al.	700/245
*	B	US-7,120,518	10-2006	Takenaka et al.	700/245
*	C	US-6,969,965	11-2005	Takenaka et al.	318/568.12
*	D	US-6,876,903	04-2005	Takenaka, Toru	700/245
*	E	US-6,697,709	02-2004	Kuroki et al.	700/245
*	F	US-7,076,337	07-2006	Kuroki et al.	700/254
*	G	US-5,872,893	02-1999	Takenaka et al.	700/245
*	H	US-5,426,586	06-1995	Ozawa, Nobuaki	701/23
*	I	US-5,594,644	01-1997	Hasegawa et al.	701/23
*	J	US-7,308,336	12-2007	Takenaka et al.	700/245
*	K	US-7,493,192	02-2009	Takenaka et al.	700/260
*	L	US-7,319,917	01-2008	Takenaka et al.	700/245
*	M	US-7,337,039	02-2008	Takenaka et al.	700/245

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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